


<b>Search Notes</b>  	<b>Application/Control No.</b>  09488969	<b>Applicant(s)/Patent Under Reexamination</b>  BAER ET AL.
	<b>Examiner</b>  Maikhanh Nguyen	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	200 , 201, 204, 205, 209, 210, 227, 231, 234, 242, 247, 253, 255, 256,273, 274 , 739 744, 760, 764, 853, 854	6/12/08	MK
707	1-5, 7, 10, 100, 102, 103R, 104.1, 200, 203-206, E17.008, E17.009	6/12/09	MK

SEARCH NOTES		
Search Notes	Date	Examiner
West Updated (USPAT, USPGPub) - See Search History	6/16/08	MK
West Updated (USPAT, USPGPub) - See Search History	11/11/08	MK
Inventor Name Search	6/12/09	MK
West Updated (USPAT, USPGPub, JPAB, DWPI, TDBD) - See Search History	6/12/09	MK
Interference Search (USPAT, USPGPub) - See Search History	6/12/09	MK
NPL Search (Google Scholar) - See Search History	6/12/09	MK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	205,209, 234, 853	6/12/09	MK
707	1, 3 ,104.1	6/12/09	MK

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